

Search Notes



Application/Control No.

10/026,618

Examiner

Emmanuel Bayard

Applicant(s)/Patent under Reexamination

LEE ET AL.

Art Unit

2638

SEARCHED

Class	Subclass	Date	Examiner
375	316	7/5/05	EB
↑	324		↑
	325		
	326		
	340		
↓	346		↓
325	354	7/5/05	EB

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EB/ASI	7/5/05	EB